Cover letter for Referencing Test Data for

FCC ID: 2AH25T2MINI Model: L1320/L1322

As the primary test lab for FCC ID: 2AH25T2MININFC Model: L1321/L1323 from Shanghai Sunmi Technology Co., Ltd., we, East China Institute of Telecommunications, according to **18 L1320L1322 and L1322 difference.pdf**.
Only NFC function for FCC ID: 2AH25T2MINI Model L1320 is removed, comparing with FCC ID: 2AH25T2MININFC Model L1321.
Only NFC function for FCC ID: 2AH25T2MINI Model L1322 is removed and the type of the printer for FCC ID: 2AH25T2MINI Model L1322 is different, comparing with FCC ID: 2AH25T2MININFC Model L1321.

Below is all the test results and referencing test data for your reference.

15B report		
	I18D00191-EMC01	Worst case of the original test report(I18D00189-EMC01)
SAR MPE report		
	I18D00191-SAR01	reuse test result of the original test report (I18D00189-SAR01)
Bluetooth report		
Peak Output power-Conducted	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
Frequency Band Edges-Conducted	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
Conducted Emission	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
Radiated Emission	I18D00191-SRD01	Worst case of the original test report (I18D00189-SRD01)
Time of Occupancy(Dwell Time)	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
20dB Bandwidth	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
Carrier Frequency Separation	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
Number of Hopping Channels	I18D00191-SRD01	reuse test result of the original test report (I18D00189-SRD01)
AC Powerline Conducted Emission	I18D00191-SRD01	Worst case of the original test report (I18D00189-SRD01)
BLE report		
Peak Output power-Conducted	I18D00191-SRD02	reuse test result of the original test report (I18D00189-SRD02)

Peak Power Spectral Density	I18D00191-SRD02	reuse test result of the original test report (I18D00189-SRD02)
6DB Bandwidth	I18D00191-SRD02	reuse test result of the original test report (I18D00189-SRD02)
Frequency Band Edges-Conducted	I18D00191-SRD02	reuse test result of the original test report (I18D00189-SRD02)
Conducted Emission	I18D00191-SRD02	reuse test result of the original test report (I18D00189-SRD02)
Radiated Emission	I18D00191-SRD02	Worst case of the original test report (I18D00189-SRD02)
AC Powerline Conducted Emission	I18D00191-SRD02	Worst case of the original test report (I18D00189-SRD02)
Wi-Fi report		
Maximun Output Power	I18D00191-SRD03	reuse test result of the original test report (I18D00189-SRD03)
Peak Power Spectral Density	I18D00191-SRD03	reuse test result of the original test report (I18D00189-SRD03)
Occupied 6DB Bandwidth	I18D00191-SRD03	reuse test result of the original test report (I18D00189-SRD03)
Bandedges Compliance	I18D00191-SRD03	reuse test result of the original test report (I18D00189-SRD03)
Transmitter Spurious Emission-Conducted	I18D00191-SRD03	reuse test result of the original test report (I18D00189-SRD03)
Transmitter Spurious Emission-Radiated	I18D00191-SRD03	Worst case of the original test report (I18D00189-SRD03)
AC Powerline Conducted Emission	I18D00191-SRD03	Worst case of the original test report (I18D00189-SRD03)
GSM/WCDMA		
Output power	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Peak-to-average power ratio	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Occuped bandwidth	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
-26dB emission bandwidth	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Band edge at antenna terminals	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Frequency stability	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Conducted spurious emission	I18D00191-SRD04	reuse test result of the original test report (I18D00189-SRD04)
Radiated	I18D00191-SRD04	Worst case of the original test report (I18D00189-SRD04)

CDMA		
Output power	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Peak-to-average power ratio	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Occuped bandwidth	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
-26dB emission bandwidth	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Band edge at antenna terminals	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Frequency stability	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Conducted spurious emission	I18D00191-SRD05	reuse test result of the original test report (I18D00189-SRD05)
Radiated	I18D00191-SRD05	Worst case of the original test report (I18D00189-SRD05)
LTE		
Output power	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)
Emission Limt	I18D00191-SRD06	Worst case of the original test report (I18D00189-SRD06)
Frequency stability	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)
Emission bandwidth	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)
Band edge compliance	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)
Conducted spurious emission	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)
Peak-to-average power ratio	I18D00191-SRD06	reuse test result of the original test report (I18D00189-SRD06)

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